

Substitute for Form 1449A/PTO (Modified)

Complete if Known

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

MAR 03 2003

Sheet

1

of

7

Application Number	10/078,282
Filing Date	February 19, 2002
First Named Inventor:	Mark W. Miles
Group Art Unit	2873
Examiner Name	Evelyn A. Lester

Attorney Docket Number

05652.P014XD2

U.S. PATENT DOCUMENTS

Exam. Initial*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (If known)			
	✓ 2,534,846			Ambrose et al.	12/19/50	
	X 3,439,973			Paul et al.	4/22/69	
	X 3,443,854			Weiss	5/13/69	
	X 3,653,741			Marks	4/4/72	
	✓ 3,656,836			de Cremoux et al.	4/18/72	
	X 3,813,265			Marks	5/28/74	
	✓ 3,955,880			Lierke	5/11/76	
	X 4,099,854			Decker et al.	7/11/78	
	X 4,228,437			Shelton	10/14/80	
	✓ 4,377,324			Durand et al.	3/22/83	
	X 4,389,096			Hori et al.	6/21/83	
	✓ 4,403,248			te Velde	9/6/83	
	X 4,445,050			Marks	4/24/84	
	✓ 4,459,182			te Velde	7/10/84	
	X 4,519,676			te Velde	5/28/85	
	X 4,531,126			Sadones	7/23/85	

FOREIGN PATENT DOCUMENTS

Exam. Initial*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code ⁵ (If known)				
	WO 95	30,924			Etalon, Inc.	11/16/95		
	EPO	0,667,5 48	A1		AT & T Corp.	8/16/95		
	JP	405,275 ,401	A1		Ikeda	10/22/93		

Examiner
Signature*Evelyn A. Lester*

Date Considered

7/12/04

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Substitute for Form 1449A/PTO (Modified)

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(use as many sheets as necessary)

Application Number	10/224,029
Filing Date	August 19, 2002
First Named Inventor:	Mark W. Miles
Group Art Unit	2873
Examiner Name	Not yet assigned

Sheet 2 of 7 Attorney Docket Number 05652.P016XD2

U.S. PATENT DOCUMENTS

Exam. Initial*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (If known)			
	X	4,663,083		Marks	5/5/87	
	X	4,681,403		te Velde et al.	7/21/87	
	X	4,748,366		Taylor	5/31/88	
	X	4,786,128		Birnbach	11/22/88	
	✓	4,790,635		Apsley	12/13/88	
	X	4,900,395		Syverson et al.	2/13/90	
	✓	4,982,184		Kirkwood	1/1/91	
	✓	5,022,745		Zaykowski et al.	6/11/91	
	✓	5,044,736		Jaskie et al.	9/3/91	
	X	5,075,796		Schildkraut et al.	12/24/91	
	✓	5,078,479		Vuilleumier	1/7/92	
	X	5,124,834		Cusano et al.	6/23/92	
	✓	5,142,414		Koehler	8/25/92	
	✓	5,153,771		Link et al.	10/6/92	
	✓	5,168,406		Nelson	12/1/92	
	X	5,228,013		Bik	7/13/93	
	✓	5,231,532		Magel et al.	7/27/93	
	✓	5,233,459		Bozler et al.	8/3/93	
	✓	5,311,360		Bloom et al.	5/10/94	
	X	5,326,430		Cronin et al.	7/5/94	

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		Office ³	Number ⁴	Kind Code ⁵ (If known)				

Examiner
Signature*Ed Glottes*Date Considered
7-12-04

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
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Sheet 3 of 7 Attorney Docket Number 05652.P014XD2

Complete if Known

Application Number	10/078,282
Filing Date	February 19, 2002
First Named Inventor:	Mark W. Miles
Group Art Unit	2873
Examiner Name	Evelyn A. Lester

U.S. PATENT DOCUMENTS

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		Number	Kind Code ² (If known)			
X	5,358,601			Cathey	10/25/94	
✓	5,381,253			Sharp et al.	1/10/95	
X	5,401,983			Jokerst et al.	3/28/95	
✓	5,459,610			Bloom et al.	10/17/95	
X	5,497,172			Doherty et al.	3/5/96	
X	5,500,635			Mott	3/19/96	
✓	5,500,761			Goossen et al.	3/19/96	
X	5,526,327			Cordova, Jr.	6/11/96	
X	5,552,925			Worley	9/3/96	
✓	5,579,149			Moret et al.	11/26/96	
✓	5,619,059			Li et al.	4/8/97	
X	5,629,790			Neukermans et al.	5/13/97	
✓	5,636,052			Arney et al.	6/3/97	
X	5,636,185			Brewer et al.	6/3/97	
✓	5,673,139			Johnson	9/30/97	
X	5,683,591			Offenberg	11/4/97	
X	5,703,710			Brinkman et al.	12/30/97	
✓	5,710,656			Goossen	1/20/98	
X	5,726,480			Pister	3/10/98	
✓	5,739,945			Tayebati	4/14/98	
X	5,784,190			Worley	7/21/98	

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Signature

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Application Number	10/078,282
Filing Date	February 19, 2002
First Named Inventor:	Mark W. Miles
Group Art Unit	2873
Examiner Name	Evelyn A. Lester

Sheet 4 of 7 Attorney Docket Number 05652.P014XD2

U.S. PATENT DOCUMENTS

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		Number	Kind Code ² (If known)			
	X	5,793,504		Stoll	8/11/98	
	✓	5,808,780		McDonald	9/15/98	
	✓	5,835,255		Miles	11/10/98	
	✓	5,943,158		Ford et al.	8/24/99	
	✓	6,055,090		Miles	4/25/00	
	X	6,100,872		Aratani et al.	8/8/00	
	✓	6,243,149	B1	Swanson et al.	6/5/01	

FOREIGN PATENT DOCUMENTS

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Signature

Date Considered
7-19-04

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Application Number	10/078,282
Filing Date	February 19, 2002
First Named Inventor:	Mark W. Miles
Group Art Unit	2873
Examiner Name	Evelyn A. Lester

Sheet	5	of	7	Attorney Docket Number	05652.P014XD2
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OTHER ART – NO PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
<i>EAL</i>	X	"Light Over Matters," June 1993, Circle No. 36	
<i>EAL</i>	✓	AKASAKA, "Three-Dimensional IC Trends," Proceedings of IEEE, Vol. 74, No. 12, Dec. 1986, pp. 1703-1714	
<i>EAL</i>	✓	ARATANI, et al., "Process and Design Considerations for Surface Micromachined Beams for a Tuneable Interferometer Array in Silicon," Proc. IEEE, Microelectromechanical Workshop, Ft. Lauderdale, FL, Feb. 7-10, 1993, pp. 230, et. seq.	
<i>EAL</i>	✓	ARATANI, K. et.al. "Surface micromachined tuneable interferometer array," Sensors and Actuators 1994, pp. 17 - 23.	
<i>EAL</i>	✓	CONNER, "Hybrid Color Display Using Optical Interference Filter Array," SID Digest 1993, pp. 577-580.	
<i>EAL</i>	✓	GOOSEN, et al., "Possible Display Applications of the Silicon Mechanical Anti-Reflection Switch," Society for Information Display, 1994.	
<i>EAL</i>	✓	GOOSEN, et al., "Silicon Modulator Based on Mechanically-Active Anti-Reflection Layer with One M Bit/Sec Capability for Fiber-in-the-Loop Applications," IEEE, Photonic Technology Letters, Sep. 1994.	
<i>EAL</i>	X	GOSCH, "West Germany Grabs the Lead in X-Ray Lithography," Electronics, Feb. 05, 1987, pp 78 - 80.	
<i>EAL</i>	X	HOWARD, "Nanometer-Scale Fabrication Techniques," VLSI Electronics: Microstructure Science, Vol. 5 1982, pp. 145-153, pp. 166-173.	
<i>EAL</i>	X	IBOTSON, et al. Comparison of XeF ₂ , and F-atom reactions with Si and siO ₂ , Applied Physics Letters. Vol. 44, No. 12, June 1984, pp 1129-1131.	
<i>EAL</i>	✓	JACKSON, "Classical Electrodynamics," John Wiley & Sons, Inc., pp. 568 - 573. <i>NO DATE PROVIDED.</i>	
<i>EAL</i>	✓	JERMAN, et al., "A Miniature Fabry-Perot Interferometer with a Corrugated Silicon Diaphram Support," Sensors and Actuators A, 1991, Vol. 29, pp. 151.	

Examiner Signature	<i>Evelyn A. Lester</i>	Date Considered	7-12-04
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Application Number	10/078,282
Filing Date	February 19, 2002
First Named Inventor:	Mark W. Miles
Group Art Unit	2873
Examiner Name	Evelyn A. Lester

Sheet 6 of 7 Attorney Docket Number 05652.P014XD2

OTHER ART – NO PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
<i>EAL</i>	X	JOHNSON, "Optical Scanners." <u>Microwave Scanning Antennas</u> , Vol. 1 p. 251 et seq. <i>NO DATE PROVIDED.</i>	
<i>EAL</i>	✓	MILES, MARK, W., "A New Reflective FPD Technology Using Interferometric Modulation," <u>Society for Information Display '97 Digest</u> , Session 7.3	
<i>EAL</i>	X	Newsbreaks, "Quantum-trench devices might operate at terahertz frequencies," <u>Laser Focus World</u> May 1993	
<i>EAL</i>	✓	OLINER, "Radiating Elements and Mutual Coupling," <u>Microwave Scanning Antennas</u> , Vol. 2, p. 131 et seq., <i>1966</i> .	
<i>EAL</i>	✓	RALEY, et al., "A Febry-Perot Microferrometer for Visible Wave Lengths," <u>IEEE Solid-State Sensor and Actuator Workshop</u> , June 1992, Hilton Head, SC.	
<i>EAL</i>	X	SCHNAKENBERG, et al. TMAHW Etchants for Silicon Micromachining, <u>1991 International Conference on Solid State Sensors and Actuators - Digest of Technical Papers</u> . pp. 815-818.	
<i>EAL</i>	✓	SPERGER, et al., "High Performance Patterned All-Dielectric Interference Colour Filter for Display Applications," <u>SID Digest</u> , 1994.	
<i>EAL</i>	X	STONE, "Radiation and Optics, An Introduction to the Classical Theory," McGraw-Hill pp. 340 - 343, <i>1963</i> .	
<i>EAL</i>	✓	WALKER, et al., "Electron-Beam-Tunable Interference Filter Spatial Light Modulator," <u>Optics Letters</u> , Vol. 13, No. 5, 1988, pp. 345, et seq.	
<i>EAL</i>	X	WILLIAMS, et al. Etch Rates for Micromachining Processing - <u>Journal of Microelectromechanical Systems</u> . Vol. 5 No. 4, December 1996, pp 256-269.	
<i>EAL</i>	X	WINTERS, et al., The etching of silicon with XeF ₂ vapor. <u>Applied Physics Letters</u> , Vol. 34, No. 1, Jan. 1979, pp. 70-73.	

Examiner Signature	<i>Evelyn A. Lester</i>	Date Considered	<i>2/2/04</i>
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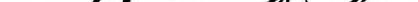
**INFORMATION DISCLOSURE
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Sheet 7 of 7 **Attorney Docket Number** 05652.P014XD2

OTHER ART – NO PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
		WINTON, John M., "A novel way to capture solar energy," Chemical Week, May 15, 1985.	
		WU, "Design of a Reflective Color LCD Using Optical Interference Reflectors," ASIA, Asia Display, Oct. 16, 1995, pp. 929-931.	

Examiner Signature		Date Considered	7-12-04
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